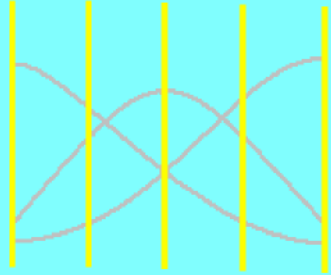


Rasch Measurement:

Advanced and Specialized Applications



Everett V. Smith, Jr.
Richard M. Smith

Rasch Measurement: Advanced and Specialized Applications

Edited by
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JAM Press is pleased to announce the new book, *Rasch Measurement: Advanced and Specialized Applications* is available. The book is available in soft cover (\$51, ISBN 978-0-975535 1-7-2) and hard cover (\$63, ISBN 978-0-975535 1-6-5). Postage and handling are additional. Information on ordering the book is located on the reverse of this announcement. Information is also available at the *Journal of Applied Measurement* web site (www.jampress.org). Please go to the JAM Press Books page on the website and scroll down to the new books section.

This book is compiled from the Understand Rasch Measurement series in the *Journal of Applied Measurement* and from a special issue of the *Journal of Applied Measurement* on multilevel measurement models guest edited by Natasha Beretvas and Akihito Kamata. To the degree possible, we have attempted to make these topics user friendly by providing a tutorial oriented perspective designed to make these models more accessible to researchers. Screenshot and control files are provided for several of the applications. The two major areas addressed are: Advanced and Specialized Applications of Rasch Models and Multilevel Measurement Rasch Models. A listing of chapters and authors is found below.

Part I. Advanced and Specialized Applications

1. Rasch analysis of rank-ordered data by *John Michael Linacre, University of Sydney, Australia*
2. Using paired comparisons to create the semantic construct of frequency by *Thomas R. O'Neill, National Council of State Boards of Nursing, Inc.*
3. Multicomponent latent trait models for complex tasks by *Susan E. Embretson, Georgia Institute of Technology and Xiangdon Yang, University of Kansas*
4. The Saltus model applied to proportional reasoning data by *Karen Draney, University of California Berkeley*
5. The Mixed-Rasch Model: An example for analyzing the meaning of response latencies in a personality questionnaire by *Mag. Dr. Michaela M. Wagner-Menghin, University of Vienna*
6. Using Rasch scaled stage scores to validate orders of hierarchical complexity of balance beam task sequences by *Michael Lamport Commons, Harvard Medical School, Eric Andrew Goodheart, Dare Institute, Alexander Pekker, University of Texas, Austin, Theo Linda Dawson, Hampshire College, Karen Draney, University of California, Berkeley, and Kathryn Marie Adams, Harvard Medical School*
7. Binary items and beyond: A simulation of computer adaptive testing using the Rasch partial credit model by *Rense Lange, Illinois State Board of Education and Integrated Knowledge Systems, Inc.*
8. The relationship between the rating scale and partial credit models and the implication of disordered thresholds of the Rasch models for polytomous responses by *Guanzhong Luo, Hong Kong Examination and Assessment Authority*
9. Instrument development tools and activities for measure validation using Rasch models: Part I by *Ed Wolfe, Virginia Tech University and Everett Smith, University of Illinois at Chicago*
10. Instrument development tools and activities for measure validation using Rasch models: Part II by *Ed Wolfe, Virginia Tech University and Everett Smith, University of Illinois at Chicago*

Part II. Multi-level Measurement Rasch Models (guest editors Natasha Beretvas, University of Texas at Austin and Akihito Kamata, Florida State University)

11. Introduction to the Special Section on the Multilevel Measurement Model for dichotomous items by *S. Natasha Beretvas, University of Texas at Austin and Akihito Kamata, Florida State University*
12. Demonstration of software programs for estimating multilevel measurement model parameters by *J. Kyle Roberts, Baylor College of Medicine and Rich Herrington, University of North Texas*
13. Mixed model estimation methods for the Rasch model by *Frank Rijmen, Francis Tuerlinckx, Michel Meulders, Dirk J. M. Smits, and Katalin Balázs, Katholieke Universiteit Leuven, Belgium*
14. Some links between classical and modern test theory via the two-level hierarchical generalized linear model by *Yasuo Miyazaki, Virginia Polytechnic Institute and State University*
15. Modeling local item dependence with the hierarchical generalized linear model by *Hong Jiao, Harcourt Assessment, Inc., Shudong Wang, Harcourt Assessment, Inc., and Akihito Kamata, Florida State University*
16. The cross-classified multilevel measurement model: An explanation and demonstration by *S. Natasha Beretvas, University of Texas at Austin, Jason L. Meyers, Pearson Educational Measurement, and Rolando A. Rodriguez, University of Texas at Austin*
17. Test equating in the presence of DIF items by *Kwang-lee Chu, Harcourt Assessment, Inc. and Akihito Kamata, Florida State University*

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